

R&D and Services

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NANOSPEC 6100UV Film Measurement Tool

SN 0307-0083

150mm Configuration

Information contained in this presentation is confidential

NANOSPEC 6100UV Film Measurement Tool

75mm to 200mm Configuration

Location warehouse Nijmegen condition “as is where is”



Model: Nanospec 6100

Utilizes non-contact spectroscopy reflectometry to measure sites as small as 10um in diameter

Computerized 1um resolution stage

Autofocus

Provides automatic generation of film thickness uniformity maps in high resolution color and 3D formats

Measurement range: 200 Å - 30um with visible light source

Continuous scanning from 210 - 800 nanometers

System Computer and Software

System Monitor, Keyboard, and Trackball

2D & 3D wafer mapping software

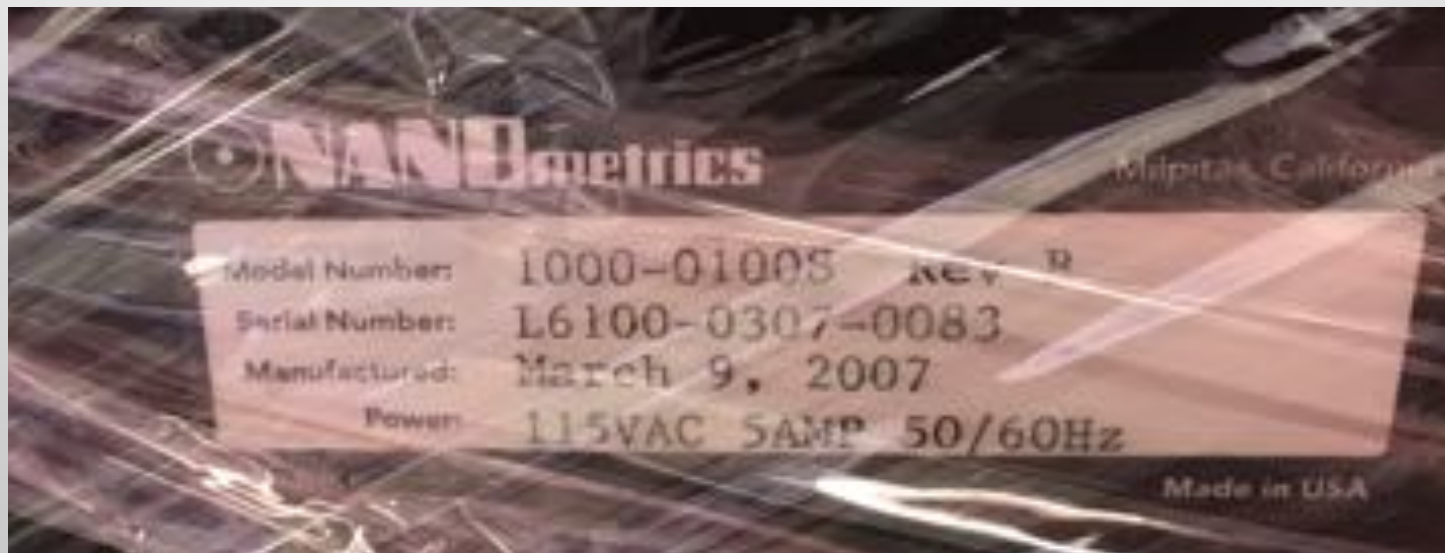
Operator Manual and Documentation



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150mm Configuration

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Solutions on Silicon BV

Your service partner for LAM Research Equipment

- **Equipment Support**
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Process design, Improvement, Fab-to-Fab Transfer and Integration
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